



9. (Previously Presented) The method of claim 1, wherein the scanning probe microscopy is atomic force microscopy, scanning tunneling microscopy, lateral force microscopy, chemical force microscopy, force modulation imaging, magnetic force microscopy, high frequency magnetic force microscopy, magnetoresistive sensitivity mapping, electric force microscopy, scanning capacitance microscopy, scanning spreading resistance microscopy, tunneling atomic force microscopy or conductive atomic force microscopy.

16. (Previously Presented) The method of claim 15 wherein the feature tag comprises a start tag.

20-36. (Canceled)